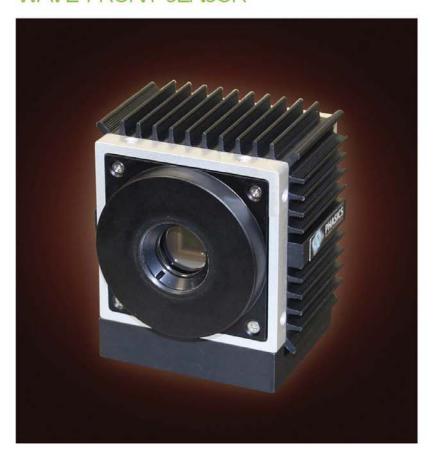
SID4 UV WAVE FRONT SENSOR



SPECIFICATIONS

Aperture dimension	$7.4 \times 7.4 \text{ mm}^2$
Spatial resolution	29.6 μm
Sampling	250 x 250
Wavelength range	250 - 400 nm
Accuracy (absolute)	10 nm RMS
Resolution (Phase)	2 nm RMS
Dynamic	> 200 µm PtV
Analysis rate	2 fps
Acquisition rate	30 fps
Computer connection	Ethernet
Dimensions (WxHxL)	45 x 30 x 100 mm
Weight	250 g

The **SID4-UV** wavefront sensor benefits from PHASICS patented technology*. It not only offers an unequalled high resolution (250x250 measurement points) but it is also compact and very easy-to-use. Thus it delivers **fast and accurate** measurement.

It is a cost-effective solution for testing quality of UV optics such as lens used in semiconductors systems (MTF, aberrations...). It also allows full surface inspection of lens, mirror, wafer...

The SID4-UV is an efficient instrument for ultraviolet laser beam measurement (Zernike coefficients, PSF, M², Strehl Ratio, beam profile...)

KEY FEATURES

- Very high resolution:
 250x250 phase pixels
- Large analysis pupil:
 7.4 x 7.4 mm²
- Broadband
- Compact
- Cost-effective

Distribution in the UK & Ireland



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